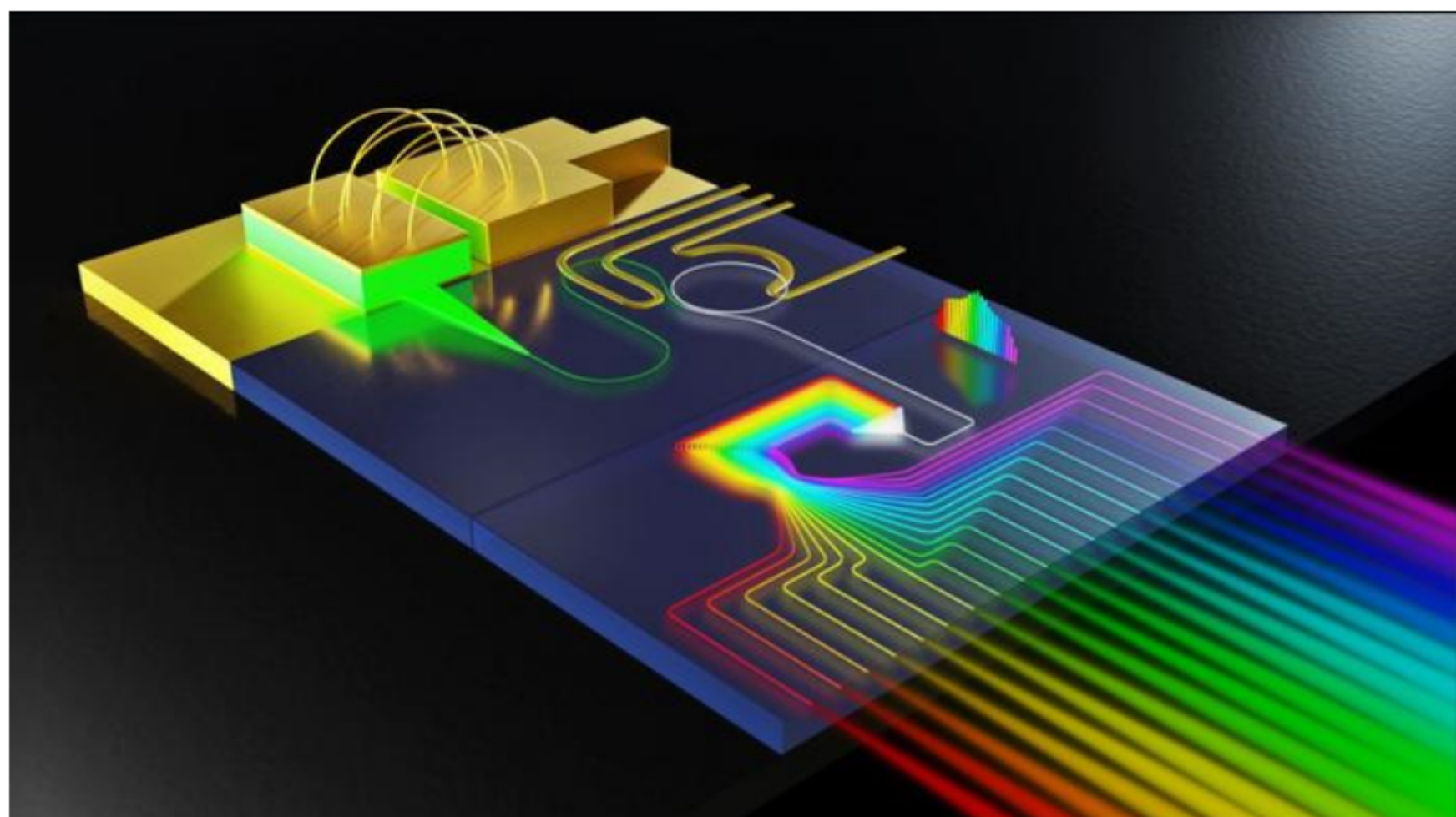




## Integrated Photonics Newsletter



### Lipson Team Develops Microcomb Source On-Chip for Modern Data Centers

Researchers from the Columbia University School of Engineering and Applied Sciences have developed a method to create a high-power frequency comb that avoids the need for large and expensive lasers and amplifiers. The team's discovery enabled the researchers to bring the power of the frequency comb on-chip, yielding a compact, high-power, multiwavelength light source. The researchers believe that the developed approach and system could find use in state-of-the-art data centers, which are already using fiber optic links to transport data, yet still typically rely on single-wavelength lasers. [Read Article](#)

## More News

[PINC Technologies Emerges from Stealth to Advance Nonlinear Photonics Tech](#)

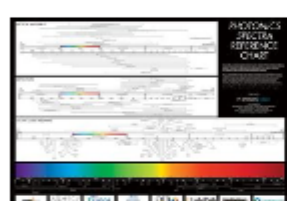
[Caltech Research Enables Coherent Spectral Broadening On-Chip](#)

[Light-Based Chip Boosts AI Power Efficiency 100-Fold](#)

[Programmable Waveguide Allows Multiple Nonlinear Functions on One Chip](#)

[Silicon PICs Company Scintil Photonics Raises \\$58M](#)

## Featured Products & Services



### [Photonics Spectra Reference Chart](#)

#### Photonics Media

This full-color, 29.5 × 20.5-inch poster of the photonics spectrum displays the major commercial laser lines, detectors, and optical materials in the ultraviolet to the far-infrared and beyond. The convenient format makes it easy to quickly find the information you need.

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### [Unlock Precision for Integrated Photonics](#)

#### Avantes BV

The NEXOS™ compact spectrometer series from Avantes offers high-speed, low-stray-light performance for OEM integration. Ideal for photonic device testing and process monitoring, it delivers precision, scalability, and flexibility for integrated photonics and other demanding optical applications.

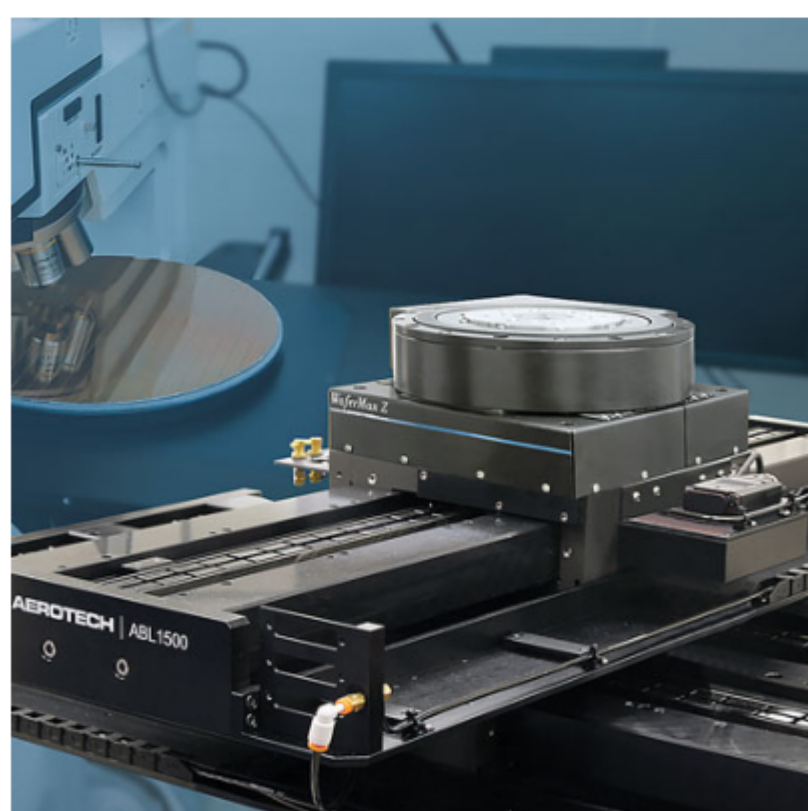
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## Latest Webinars



### Advanced Motion Control for Semiconductor Metrology

Tue, Nov 18, 2025 1:00 PM - 2:00 PM EST

Explore how advanced motion control technologies are transforming semiconductor inspection and metrology. This session examines precision motion systems used in wafer inspection, SWLI, SEM/FIB, AFM, and reticle or mask inspection, highlighting how error motions impact performance and how system-level optimization, environmental control, and advanced algorithms achieve nanometer-level precision and maximum throughput. Presented by Aerotech.

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